



IFW

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Heinz LIPPUNER

Application No.: 10/565,966

Filed: April 11, 2006

Docket No.: 126752

For: METHOD FOR CHECKING OR CALIBRATING THE ANGLE-DEPENDENT
ALIGNMENT OF A HIGH-PRECISION TEST PIECE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

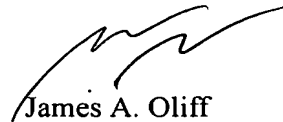
Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of one or more non-English language reference is discussed in the present specification. See Reference 3.
- ☒ 3. One or more reference cited herein was cited in a counterpart foreign application. An English language version of the European search report is attached for the Examiner's information. See Reference 1.
- ☒ 4. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. According to the Notification of Acceptance in this file, a copy of each reference is already in the PTO file. Thus, no copy of any such reference is attached. See Reference 2.

- ☒ 5. An English language Abstract of one or more non-English language reference is attached hereto. See References 1 and 2.

Respectfully submitted,


James A. Oliff
Registration No. 27,075

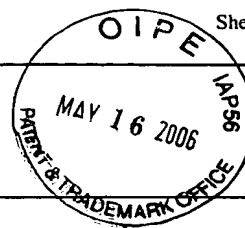
Scott M. Schulte
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JAO:SMS/jtp

Date: May 16, 2006

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<p>DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p>
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Sheet 1 of 1

Form PTO-1449
(REV. 1/06)US Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
126752APPLICATION NO.
10/565,966

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT
Heinz LIPPUNERFILING DATE
April 11, 2006

GROUP

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	1	SU 763 682 A	9/15/1980	Russia	X	

OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)
	2	Hilmar Ingensand, "TPM - Ein Neues Gerät zur vollautomatischen Prüfung von Teilkreisen in elektronischen Theodoliten", X. Internationaler Kurs für Ingenieurvermessung, Technische Universität München, 12. - 17.9.1988. (w/ Abstract).
	3	Andreas Rützler, "Kalibereinrichtung für Theodoliten", Institut für allgemeine Elektrotechnik und elektrische Messtechnik, Technische Universität Graz, Oktober 1991.

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: May 16, 2006